

## Publikationen

- (2017): Chapter 3: Fundamentals of CAFM Operation Modes. In: Conductive Atomic Force Microscopy: Applications in Nanomaterials, Weinheim.
- (2016): Nanoscale electrical conductivity of laser-sintered Ge nanoparticle layers. In: The 8th International Conference On Technological Advances Of Thin Films and Surface Coatings (ThinFilms 2016), Singapur, Singapur.
- (2016): Nanoscale characterization of laser-sintered Ge nanoparticle layers. In: 2nd International Conference on Functional Integrated nano Systems (nanoFIS), Graz, Österreich.
- (2016): Characterization of the photocurrents generated by the laser of atomic force microscopes. In: Review of Scientific Instruments, vol. 87, no. 8. DOI: 10.1063/1.4960597.
- (2015): Atomic Force Microscopy analysis of laser-sintered Germanium nanoparticles for thermoelectric applications. In: 3rd International Congress on Energy Efficiency and Energy Related Materials (ENEFM), Oludeniz, Türkei.
- (2015): A review of physical characterization methods for nanostructured thermoelectric materials. Invited Talk. In: 3rd International Congress on Energy Efficiency and Energy Related Materials (ENEFM), Oludeniz, Türkei.
- (2015): Differential  $3\omega$  method for measuring thermal conductivity of AlN and Si<sub>3</sub>N<sub>4</sub> thin films. In: Thin Solid Films, vol. 591 Part B, pp. 267-270. DOI: 10.1016/j.tsf.2015.03.031.
- (2015): Use of Coated-Metal Particles in Rear Busbar Pastes to Reduce Silver Consumption. In: IEEE Journal of Photovoltaics, vol. 5, no. 2, pp. 534-537. DOI: 10.1109/JPHOTOV.2014.2388080.
- (2014): The differential  $3\omega$  method for measuring the thermal conductivity of AlN and Si<sub>3</sub>N<sub>4</sub> thin films. In: 16th International Conference on Thin Films (ICTF16), Dubrovnik, Kroatien.
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- (2013): Scanning probe microscopy based electrical characterization of thin dielectric and organic semiconductor films. In: Microelectronics Reliability, vol. 53, no. 9-11, pp. 1430-1433.
- (2013): Analysis of crystal defects on GaN based semiconductors with advanced scanning probe microscope technique. In: Thin Solid Films, vol. 544, no. Oktober, pp. 139-143.
- (2012): Analysis of crystal defects on GaN-based semiconductors with advanced scanning probe microscope techniques. Invited Talk. In: 6th International Conference on Technological Advances of Thin Films & Surface Coatings (THINFILMS2012), Singapur, Singapur.
- (2011): Capacitance and Conductivity Mapping of Organic Films and Devices with Non-Contact SPM Methods. In: International Workshop on Scanning Probe Microscopy for Energy Applications, Mainz.
- (2010): Intermittent-Contact Scanning Capacitance Analysis of Thin Dielectric Films and Semiconductor Devices. Invited Talk. In: 5th International Conference on Technological Advances of Thin Films & Surface Coatings, Harbin, China.

(2006): Raster-Sonden-Mikroskopie (SPM) in der Fehler- und Zuverlässigkeitsanalytik. In: VDE Fehlermechanismen bei kleinen Geometrien, Grainau.

(2005): Intermittent Contact Scanning Capacitance Microscopy-First Results. In: Workshop on Scanning Probe Microscopy and Related Techniques, Villach, Österreich.

